

Form PTO 1449  
(Modified)U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

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SERIAL NO.

New Application

## LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Yasuyoshi ITOH, et al.

FILING DATE

Herewith

GROUP

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA	5,768,192	06/16/98	Boaz EITAN			
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
TT	AO	2000-260887	09/22/00	Japan		
TT	AP	5-75133	03/26/93	Japan (with English extract)		X ✓
TT	AQ	2002-26149	01/25/02	Japan (with partial English translation)		X ✓
	AR					X ✓
	AS					
	AT					
	AU					

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

TT	AV	Ilan BLOOM, et al., "NROM™ - A NEW NON-VOLATILE MEMORY TECHNOLOGY: FROM DEVICE TO PRODUCTS", Microelectronic Engineering 59, 2001, pgs. 213 - 223.	
TT	AW	Toshiyuki TOYOSHIMA, et al., "0.1µm LEVEL CONTACT HOLE PATTERN FORMATION WITH KrF LITHOGRAPHY BY RESOLUTION ENHANCEMENT LITHOGRAPHY ASSISTED BY CHEMICAL SHRINK (RELACS)", IEEE, IEDM, 1998, pgs. 333 - 336.	
TT	AX	J. De BLAUWE, et al., "Si-Dot NON-VOLATILE MEMORY DEVICE", Extended Abstracts of the 2001 International Conference on Solid State Devices and Materials, Tokyo, 2001, pgs. 518 - 519.	
TT	AY	Boaz EITAN, et al., "CAN NROM, A 2-BIT, TRAPPING STORAGE NVM CELL, GIVE A REAL CHALLENGE TO FLOATING GATE CELLS?", Presented at the International Conference on Solid State Devices and Materials, Tokyo, 1999, pgs. 1/3 - 3/3.	
TT	AZ	Eli LUSKY, et al., "ELECTRON DISCHARGE MODEL OF LOCALLY-TRAPPED CHARGE IN OXIDE-NITRIDE-OXIDE (ONO) GATES FOR NROM™ NON-VOLATILE SEMICONDUCTOR MEMORY DEVICES", Presented at the Solid State Device and Materials Conference (SSDM 2001), Sep. 2001, Tokyo, Japan, pgs. 1 - 2.	<input type="checkbox"/> Additional References sheet(s) attached

Examiner

Date Considered

\*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.